



FCC CFR47 PART 15 SUBPART C

Bluetooth

CERTIFICATION TEST REPORT

FOR

GSM/WCDMA/LTE Phone + BT/BLE, DTS b/g/n

MODEL NUMBER : SM-J320F/DS, SM-J320F, SM-J320G/DS

FCC ID: A3LSMJ320F

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Prepared for

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Revision History

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1. ATTESTATION OF TEST RESULTS

COMPANY NAME: SAMSUNG ELECTRONICS CO., LTD.
EUT DESCRIPTION: GSM/WCDMA/LTE Phone + BT/BLE, DTS b/g/n
MODEL NUMBER: SM-J320F/DS, SM-J320F, SM-J320G/DS
SERIAL NUMBER: 4200636ACE09A200 (RADIATED);
42006DBED0E0A200 (CONDUCTED)
DATE TESTED: DEC 03, 2015 – JAN 11, 2016

APPLICABLE STANDARDS	
STANDARD	TEST RESULTS
CFR 47 Part 15 Subpart C	Pass

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

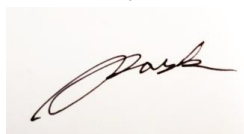
Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

Approved & Released For
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CY Choi
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Tested By:



SungGil Park
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UL Korea, Ltd.

2. TEST METHODOLOGY

The tests documented in this report were performed in accordance with ANSI C63.10-2009, FCC CFR 47 Part 2, FCC CFR 47 Part 15.

3. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro	
☒	Chamber 1
☒	Chamber 2

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at <http://www.iasonline.org/PDF/TL/TL-637.pdf>.

4. CALIBRATION AND UNCERTAINTY

4.1. MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

4.2. SAMPLE CALCULATION

Where relevant, the following sample calculation is provided:

$$\begin{aligned} \text{Field Strength (dBuV/m)} &= \text{Measured Voltage (dBuV)} + \text{Antenna Factor (dB/m)} + \\ &\text{Cable Loss (dB)} - \text{Preamplifier Gain (dB)} \\ 36.5 \text{ dBuV} + 18.7 \text{ dB/m} + 0.6 \text{ dB} - 26.9 \text{ dB} &= 28.9 \text{ dBuV/m} \end{aligned}$$

4.3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus:

PARAMETER	UNCERTAINTY
Conducted Disturbance, 0.15 to 30 MHz	2.32 dB
Radiated Disturbance, Below 1GHz	4.14 dB
Radiated Disturbance, Above 1 GHz	5.97 dB

Uncertainty figures are valid to a confidence level of 95%.

5. EQUIPMENT UNDER TEST

5.1. DESCRIPTION OF EUT

The EUT is GSM/WCDMA/LTE Phone + BT/BLE, DTS b/g/n.
This test report addresses the DSS (BT) operational mode.

SM-J320F, SM-J320F/DS and SM-J320G/DS are same hardware but for different number of SIM card slot. SM-J320F has one slot. SM-J320F/DS and SM-J320G/DS are dual SIM version.

Also SM-J320F and SM-J320G/DS didn't support non-USA LTE band(disabled by SW).

SM-J320F/DS was used for the test.

5.2. MAXIMUM OUTPUT POWER

The transmitter has a maximum conducted output power as follows:

Frequency Range [MHz]	Mode	Power Mode	Output Power [dBm]	Output Power [mW]
2402 - 2480	Basic GFSK	Average	10.17	10.39
		Peak	10.47	11.15
	Enhanced Pi/4-DPSK	Average	9.68	9.29
		Peak	11.71	14.83
	Enhanced 8PSK	Average	9.69	9.31
		Peak	11.97	15.72

Note: GFSK, Pi/4-DQPSK, 8PSK average Power are all investigated, The GFSK & 8PSK Power are the worst case. Testing is based on this mode to showing compliance. For average power data please refer to section 8.6.

5.3. DESCRIPTION OF AVAILABLE ANTENNAS

The radio utilizes an FPCB antenna, with a maximum gain of -5.37 dBi.

5.4. WORST-CASE CONFIGURATION AND MODE

Radiated emission and power line conducted emission were performed with the EUT set to transmit at the channel with highest output power as worst-case scenario.

The fundamental of the EUT was investigated in three orthogonal orientations X, Y and Z it was determined that X orientation was worst-case orientation; therefore, all final radiated testing was performed with the EUT in X orientation.

5.5. DESCRIPTION OF TEST SETUP

SUPPORT EQUIPMENT

Support Equipment List				
Description	Manufacturer	Model	Serial Number	FCC ID
Charger	SAMSUNG	ETA0U83EWE	DW1FC09KS/A-E	N/A
Data Cable	SAMSUNG	ECB-DU68WE	N/A	N/A
Earphone	SAMSUNG	EHS61ASFWE	N/A	N/A

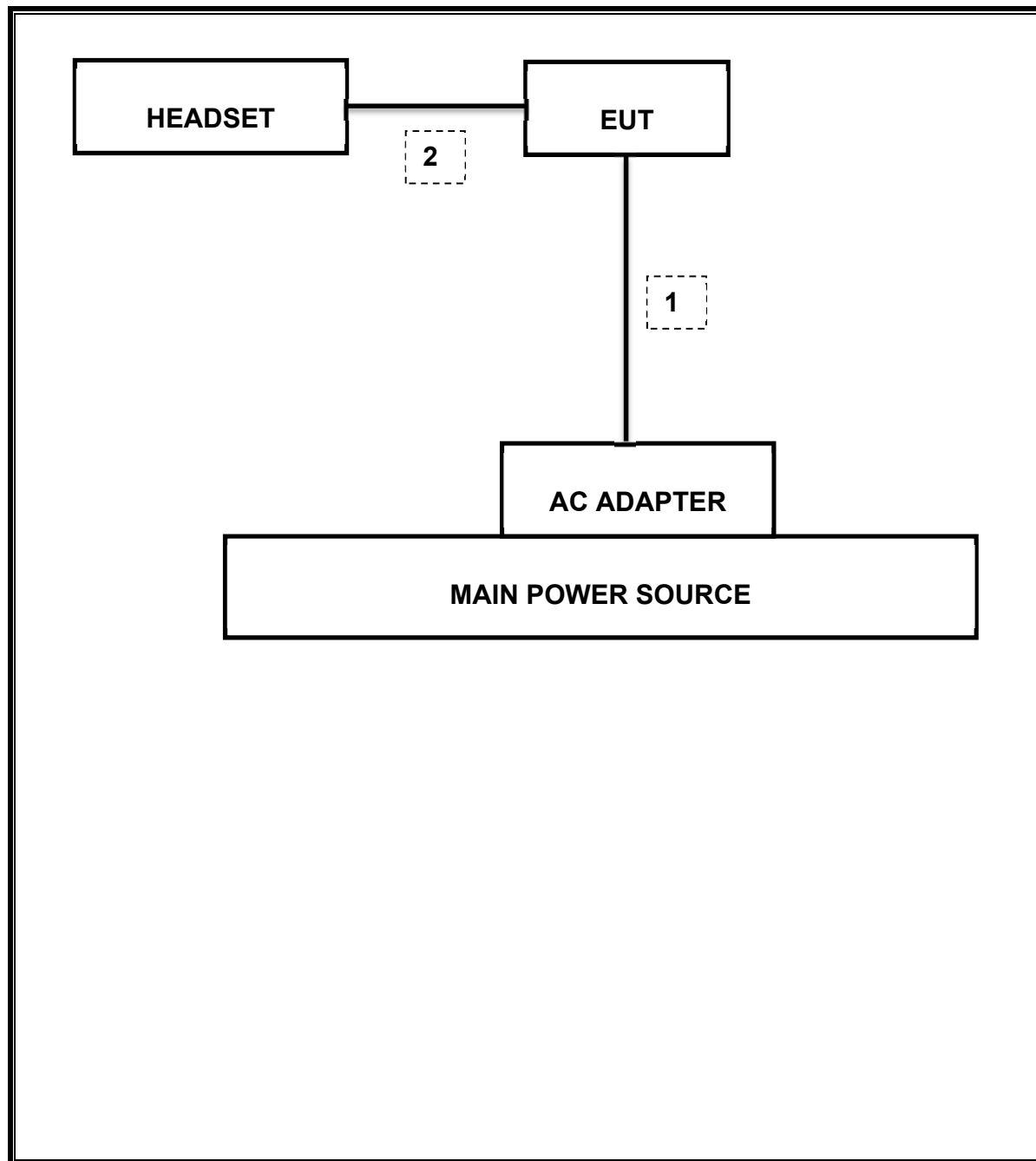
I/O CABLES

I/O Cable List						
Cable No	Port	# of identical ports	Connector Type	Cable Type	Cable Length (m)	Remarks
1	DC Power	1	Mini-USB	Shielded	0.8m	N/A
1	Audio	1	Mini-Jack	Unshielded	1.0m	N/A

TEST SETUP

The EUT is continuously communicating to the Bluetooth tester during the tests.
EUT was set in the Hidden menu mode to enable BT communications.

SETUP DIAGRAM FOR TESTS



6. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was utilized for the tests documented in this report:

Test Equipment List				
Description	Manufacturer	Model	S/N	Cal Due
Antenna, Bilog, 30MHz-1GHz	SCHWARZBECK	VULB9163	750	11-17-16
Antenna, Bilog, 30MHz-1GHz	SCHWARZBECK	VULB9163	749	04-25-17
Antenna, Horn, 18 GHz	ETS	3115	00167211	09-26-16
Antenna, Horn, 18 GHz	ETS	3115	00161451	05-17-17
Antenna, Horn, 18 GHz	ETS	3117	00168724	06-17-17
Antenna, Horn, 18 GHz	ETS	3117	00168717	06-17-17
Antenna, Horn, 40 GHz	ETS	3116C	00166155	09-23-16
Antenna, Horn, 40 GHz	ETS	3116C-PA	00168841	08-24-17
Preamplifier, 1000 MHz	Sonoma	310N	341282	08-18-16
Preamplifier, 1000 MHz	Sonoma	310N	351741	08-18-16
Preamplifier, 18 GHz	Miteq	AFS42-00101800-25-S-42	1876511	08-18-16
Preamplifier, 18 GHz	Miteq	AFS42-00101800-25-S-42	1896138	08-18-16
Spectrum Analyzer, 44 GHz	Agilent / HP	N9030A	MY54170614	08-19-16
Spectrum Analyzer, 44 GHz	Agilent / HP	N9030A	MY54490312	08-19-16
Bluetooth Tester	TESCOM	TC-3000C	3000C000546	08-18-16
Average Power Sensor	R&S	NRZ-Z91	102681	08-18-16
Average Power Sensor	Agilent / HP	U2000	MY54270007	08-18-16
EMI Test Receive, 40 GHz	R&S	ESU40	100439	08-19-16
EMI Test Receive, 40 GHz	R&S	ESU40	100457	08-19-16
EMI Test Receive, 3 GHz	R&S	ESR3	101832	08-19-16
Attenuator / Switch driver	HP	11713A	3748A04272	N/A
Low Pass Filter 3GHz	Micro-Tronics	LPS17541	009	08-18-16
Low Pass Filter 3GHz	Micro-Tronics	LPS17541	015	08-18-16
High Pass Filter 5GHz	Micro-Tronics	HPS17542	009	08-18-16
High Pass Filter 6GHz	Micro-Tronics	HPM17543	010	08-18-16
High Pass Filter 5GHz	Micro-Tronics	HPS17542	016	08-18-16
High Pass Filter 6GHz	Micro-Tronics	HPM17543	015	08-18-16
LISN	R&S	ENV-216	101836	08-19-16
LISN	R&S	ENV-216	101837	08-19-16
Combiner	WEINSCHEL	1575	2151	08-20-16

7. SUMMARY TABLE

FCC Part Section	Test Description	Test Limit	Test Condition	Test Result	Worst Case
2.1049	Occupied Band width (99%)	N/A	Conducted	Pass	1.194 MHz
2.1051, 15.247 (d)	Band Edge / Conducted Spurious Emission	-20dBc		Pass	-44.558 dBm
15.247 (b)(1)	TX conducted output power	<21dBm		Pass	11.965 dBm (Peak)
15.247 (a)(1)	Hopping frequency separation	> 25KHz		Pass	1 MHz
15.247 (a)(1)(iii)	Number of Hopping channels	More than 15 non-overlapping channels		Pass	79
15.247 (a)(1)(iii)	Avg Time of Occupancy	< 0.4sec		Pass	0.349 sec
15.207 (a)	AC Power Line conducted emissions	Section 10	Power Line conducted	Pass	46.93 dBuV (QP)
15.205, 15.209	Radiated Spurious Emission	< 54dBuV/m	Radiated	Pass	43.52 dBuV/m (AV)

8. ANTENNA PORT TEST RESULTS

8.1. 20 dB AND 99% BANDWIDTH

LIMITS

None; for reporting purposes only.

TEST PROCEDURE

DA 00-705: The transmitter output is connected to a spectrum analyzer. The RBW is set to $\geq$ 1% of the 20 dB bandwidth. The VBW is set to $\geq$ RBW. The sweep time is coupled.

RESULTS

8.1.1. BASIC DATA RATE GFSK MODULATION

Channel	Frequency [MHz]	20 dB Bandwidth [MHz]	99% Bandwidth [MHz]
Low	2402	0.894	0.830
Mid	2441	0.824	0.828
High	2480	0.827	0.857
Worst		0.894	0.857

8.1.2. ENHANCED DATA RATE $\pi/4$ -DQPSK MODULATION

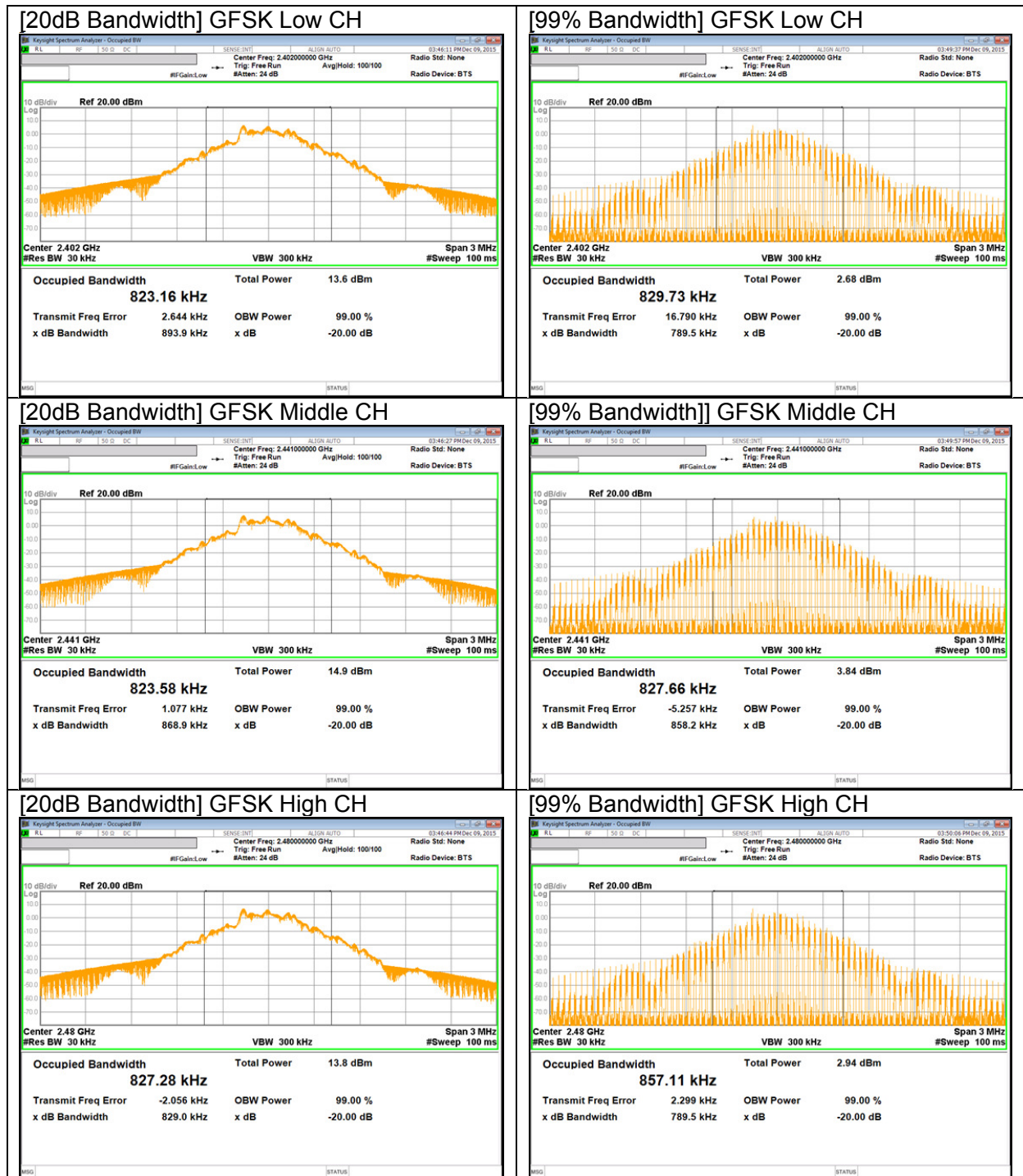
Channel	Frequency [MHz]	20 dB Bandwidth [MHz]	99% Bandwidth [MHz]
Low	2402	1.255	1.164
Mid	2441	1.256	1.164
High	2480	1.256	1.164
Worst		1.256	1.164

8.1.3. ENHANCED DATA RATE 8PSK MODULATION

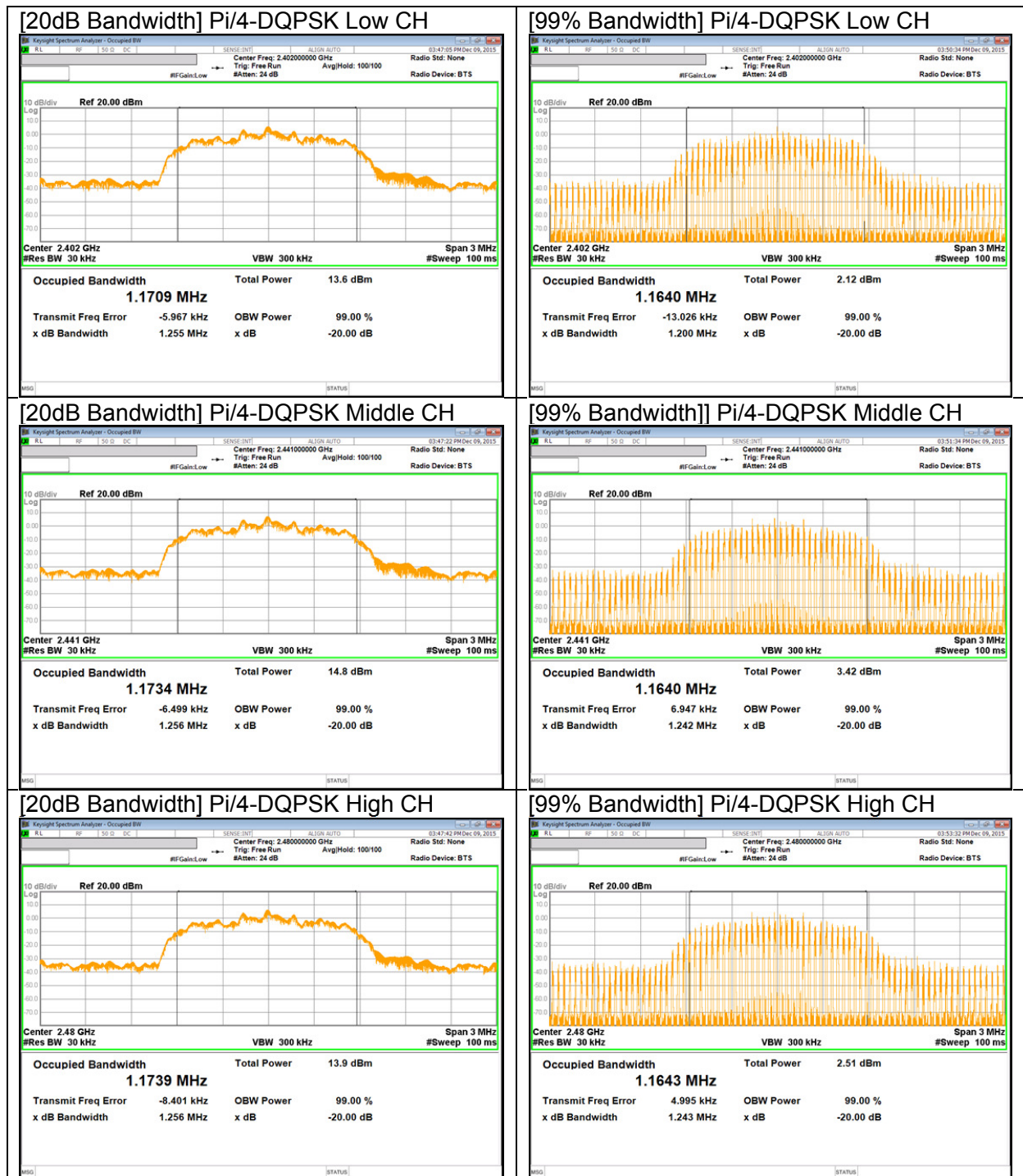
Channel	Frequency [MHz]	20 dB Bandwidth [MHz]	99% Bandwidth [MHz]
Low	2402	1.241	1.164
Mid	2441	1.222	1.194
High	2480	1.222	1.164
Worst		1.241	1.194

8.1.4. 20 dB AND 99% BANDWIDTH PLOTS

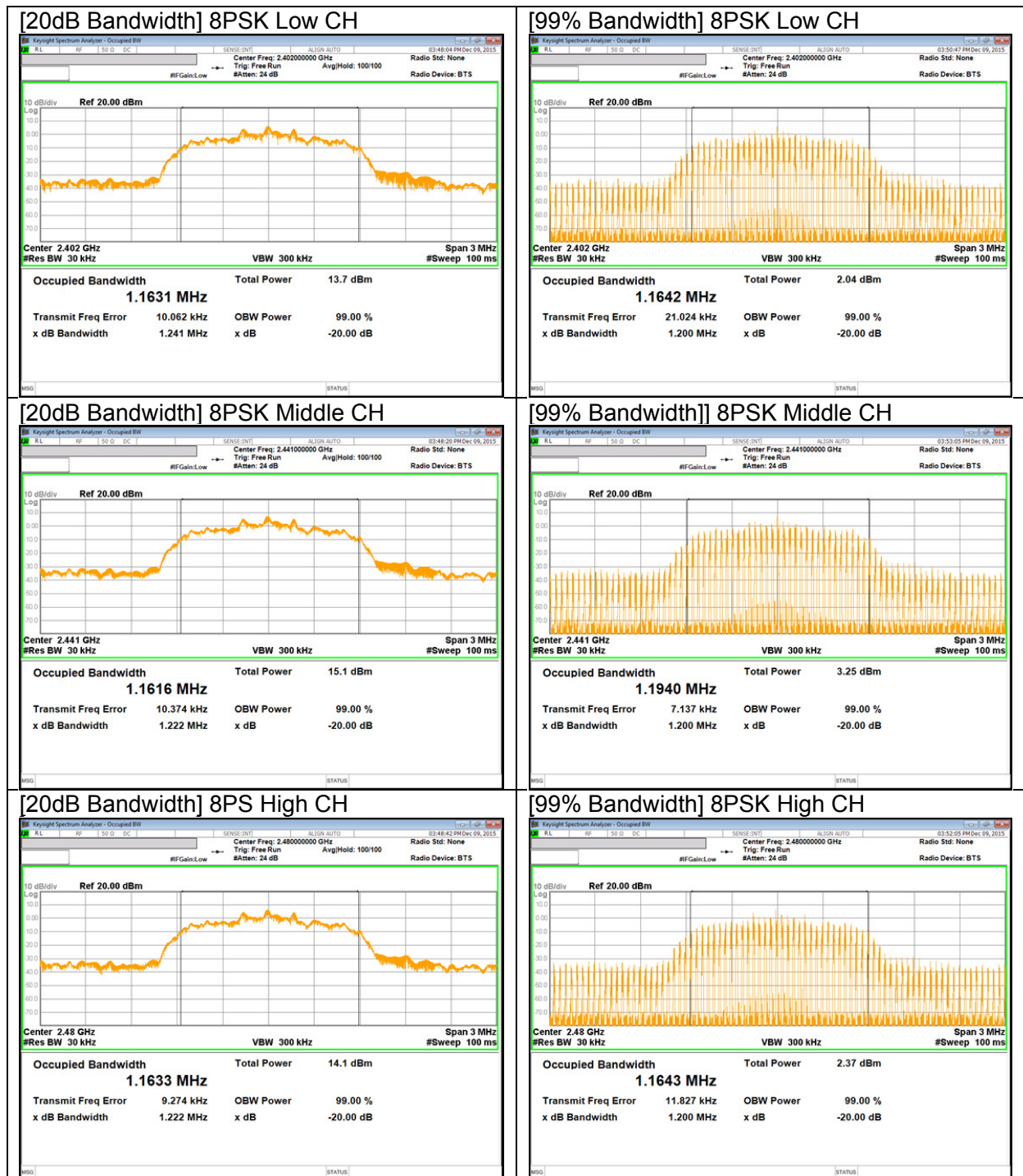
GFSK BANDWIDTH



Pi/4-DQPSK BANDWIDTH



8PSK BANDWIDTH



8.2. HOPPING FREQUENCY SEPARATION

LIMIT

FCC §15.247 (a) (1)

Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater.

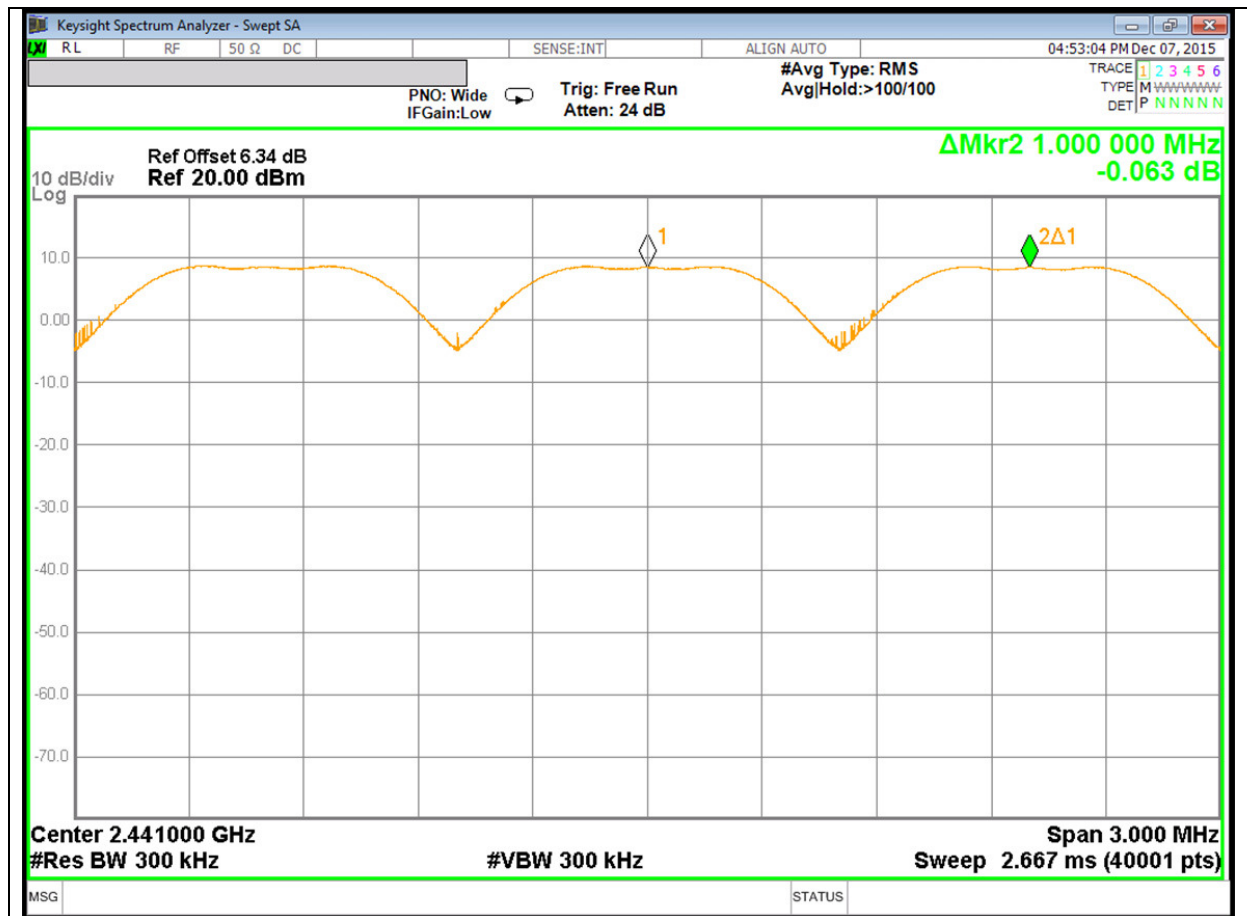
Alternatively, frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW.

TEST PROCEDURE

DA 00-705: The transmitter output is connected to a spectrum analyzer. The RBW is set to 300 kHz and the VBW is set to 300 kHz. The sweep time is coupled.

RESULTS

HOPPING FREQUENCY SEPARATION PLOT



8.3. NUMBER OF HOPPING CHANNELS

LIMIT

FCC §15.247 (a) (1) (iii)

Frequency hopping systems in the 2400 – 2483.5 MHz band shall use at least 15 non-overlapping channels.

TEST PROCEDURE

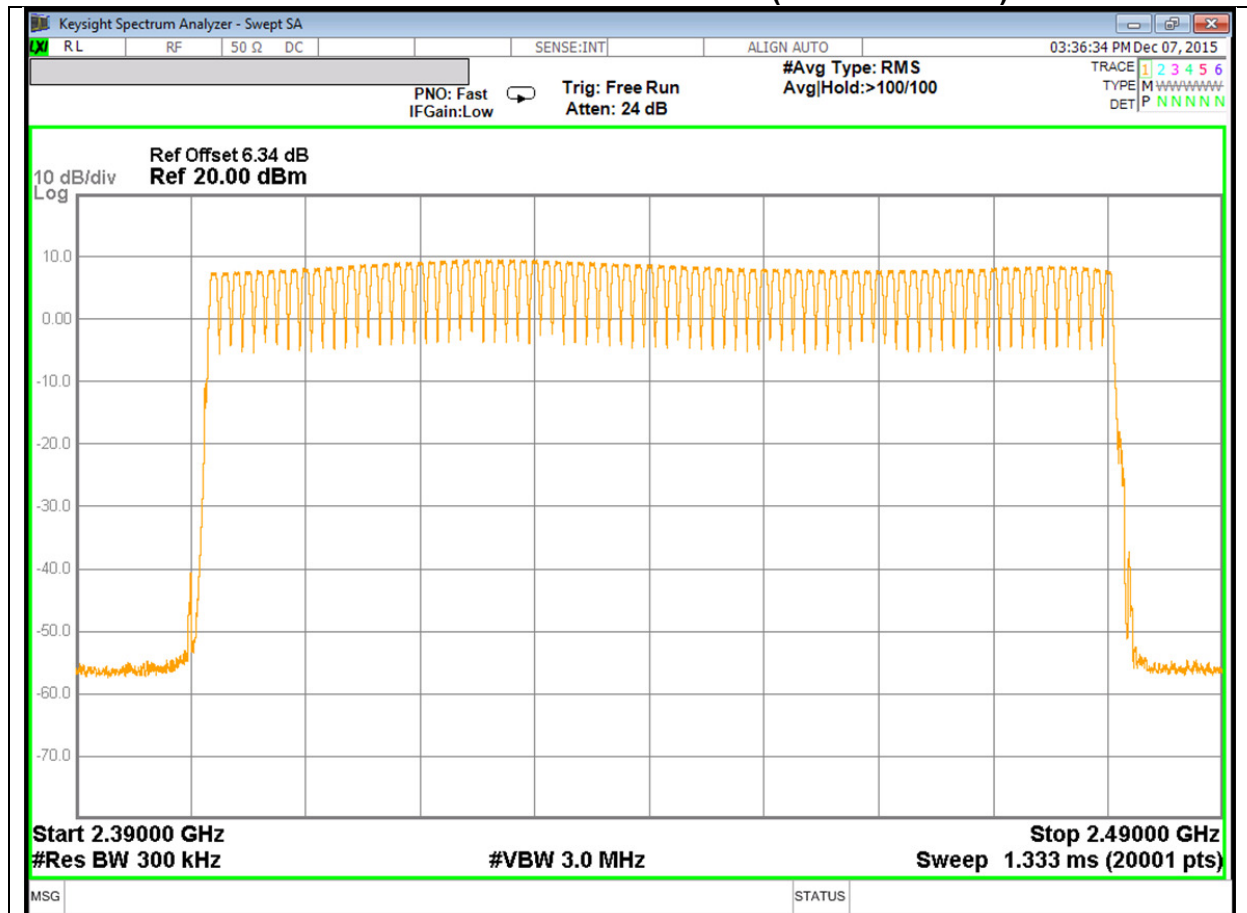
DA 00-705: The transmitter output is connected to a spectrum analyzer. The span is set to cover the entire authorized band, in either a single sweep or in multiple contiguous sweeps. The RBW is set to a maximum of 1 % of the span. The analyzer is set to Max Hold.

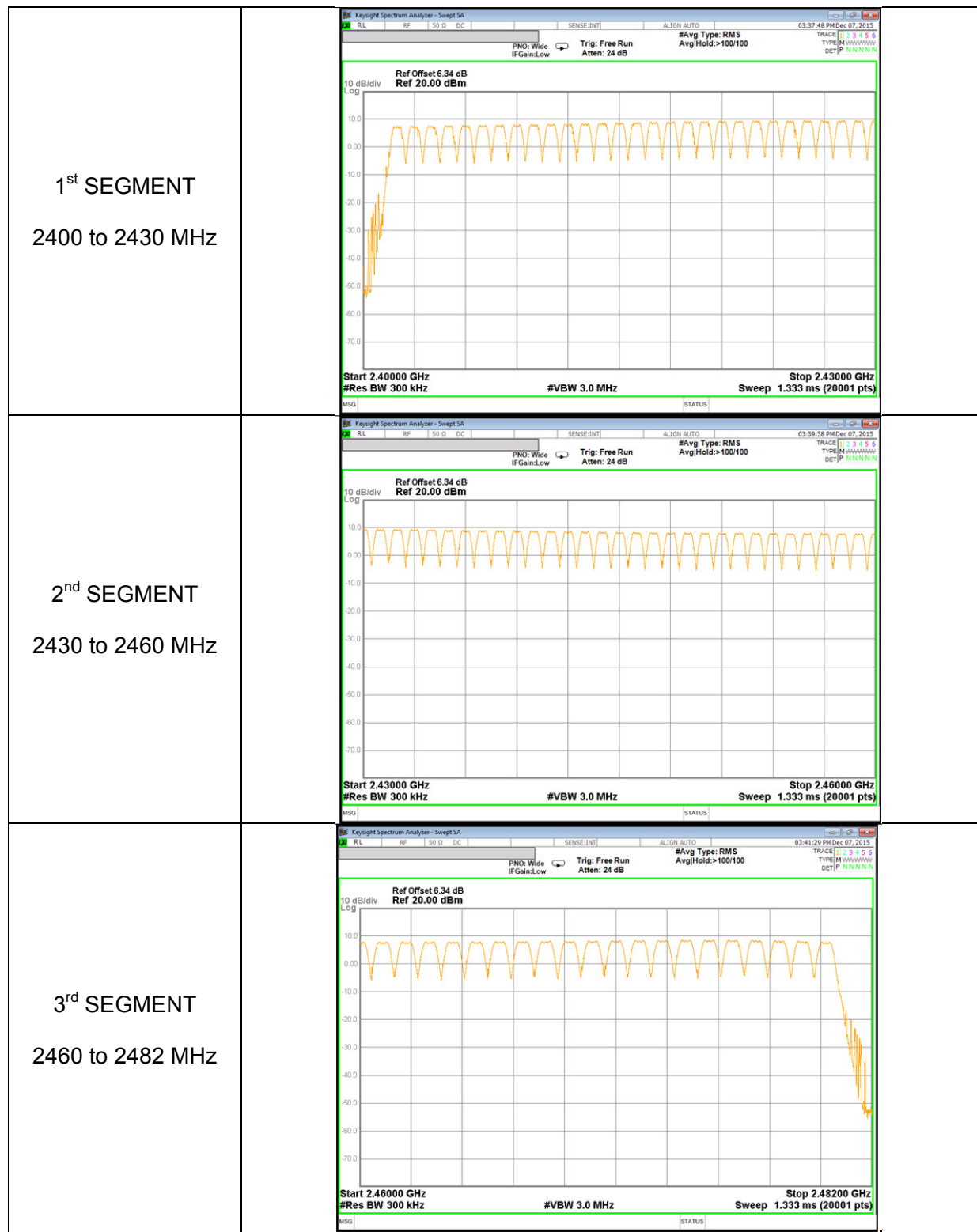
RESULTS

Normal Mode: 79 Channels observed.

NUMBER OF HOPPING CHANNELS PLOTS

NUMBER OF HOPPING CHANNELS (100 MHZ SPAN)





8.4. AVERAGE TIME OF OCCUPANCY

LIMIT

FCC §15.247 (a) (1) (iii)

The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed.

TEST PROCEDURE

The transmitter output is connected to a spectrum analyzer. The span is set to 0 Hz, centered on a single, selected hopping channel. The width of a single pulse is measured in a fast scan. The number of pulses is measured in a 3.16 second scan, to enable resolution of each occurrence.

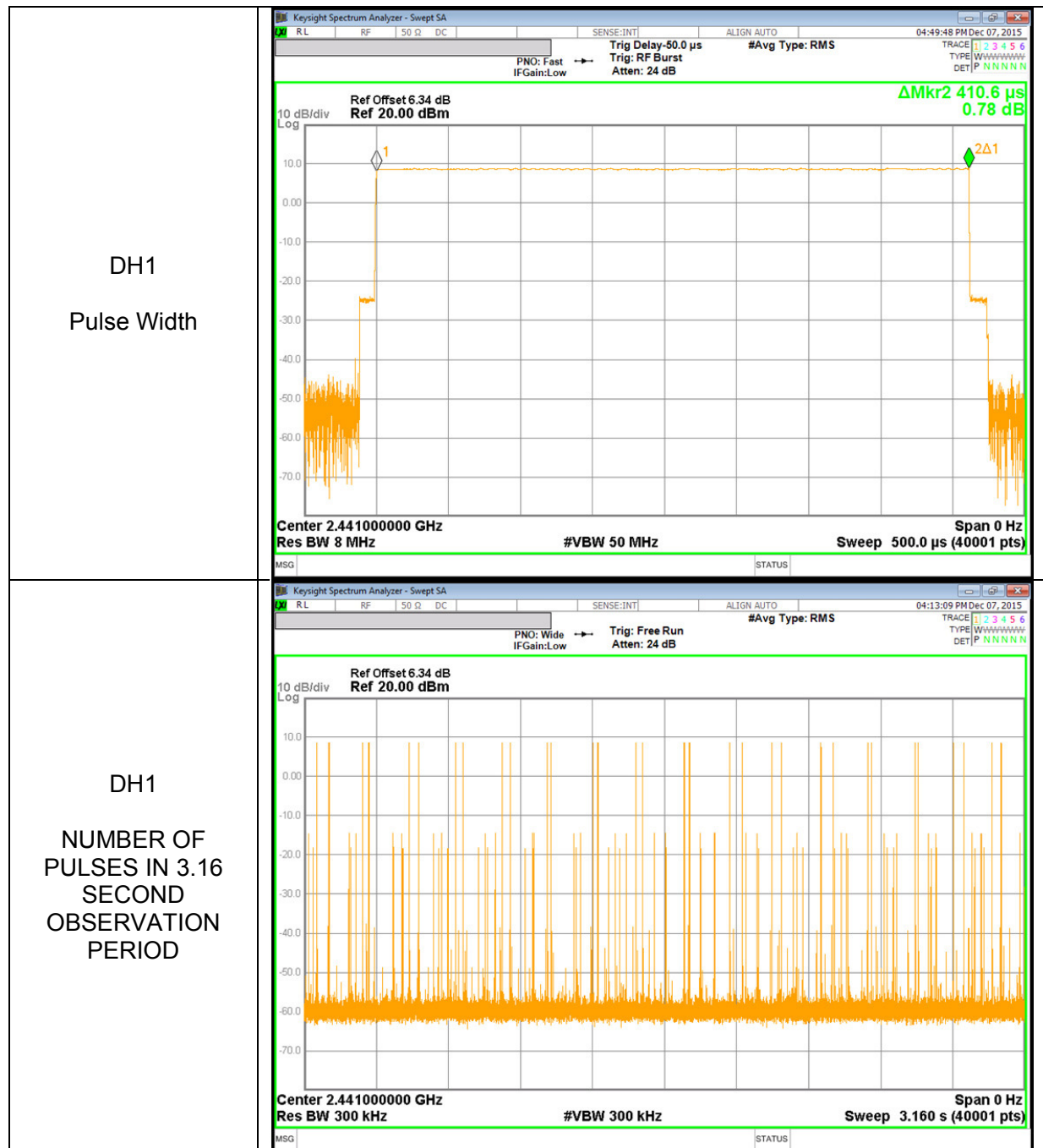
The average time of occupancy in the specified 31.6 second period (79 channels * 0.4 s) is equal to $10 * (\# \text{ of pulses in } 3.16 \text{ s}) * \text{pulse width}$.

For AFH mode, the average time of occupancy in the specified 8 second period (20 channels * 0.4 seconds) is equal to $10 * (\# \text{ of pulses in } 0.8 \text{ s}) * \text{pulse width}$.

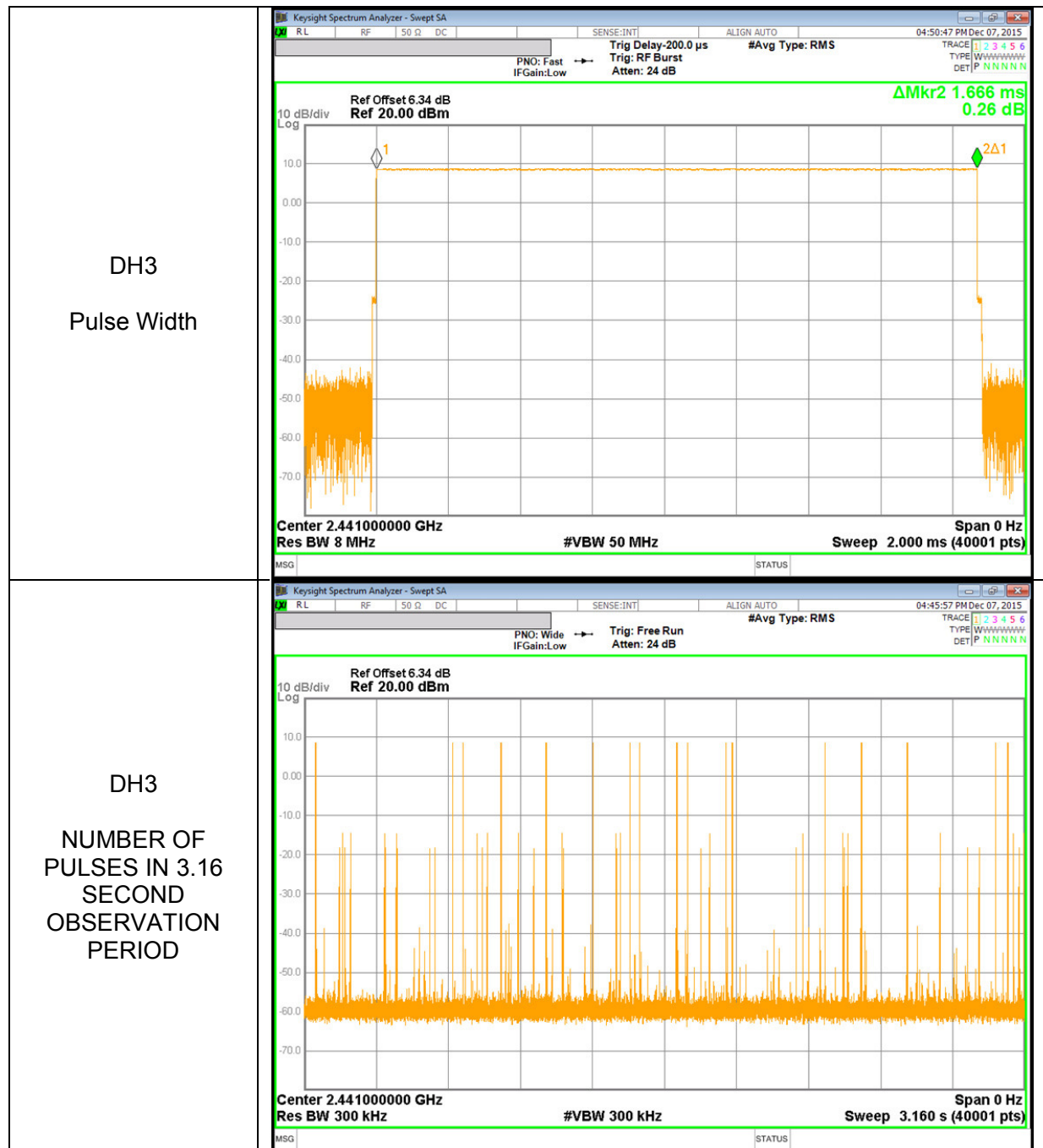
RESULTS

DH Packet	Pulse Width [msec]	Number of Pulses in 3.16 seconds	Average Time of Occupancy [sec]	Limit [sec]	Margin [sec]
GFSK Normal					
DH1	0.411	32	0.131456	0.4	-0.2685
DH3	1.667	17	0.283390	0.4	-0.1166
DH5	2.915	12	0.349800	0.4	-0.0502
GFSK AFH					
DH Packet	Pulse Width [msec]	Number of Pulses in 0.8 seconds	Average Time of Occupancy [sec]	Limit [sec]	Margin [sec]
DH1	0.411	8	0.032864	0.4	-0.36714
DH3	1.667	4.25	0.070848	0.4	-0.32915
DH5	2.915	3	0.087450	0.4	-0.31255

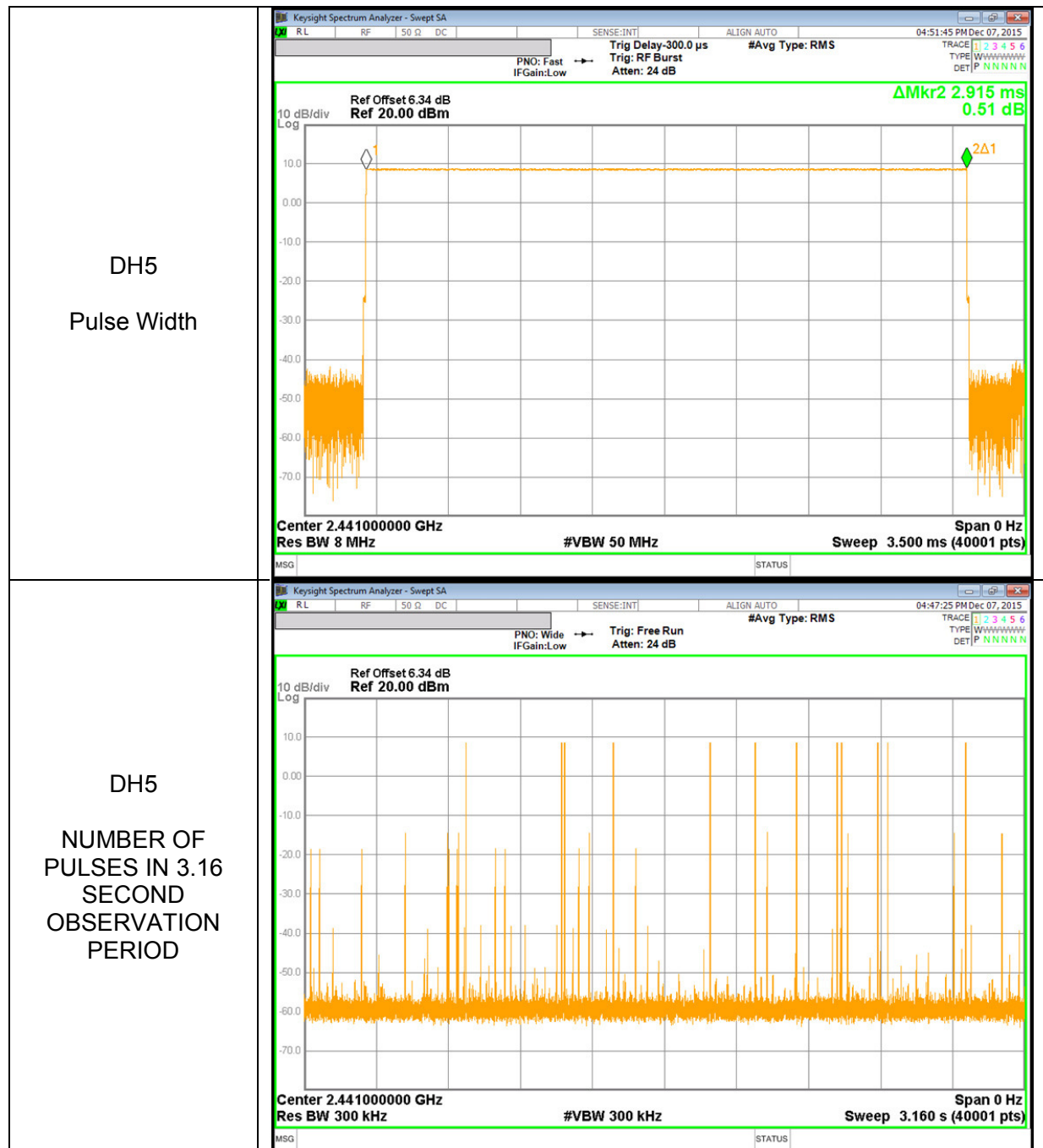
DH1



DH3



DH5



8.5. OUTPUT POWER

LIMIT

§15.247 (b) (1)

The maximum antenna gain is less than 6 dBi, therefore the limit is 21 dBm.

TEST PROCEDURE

DA 00-705: The transmitter output is connected to a spectrum analyzer the analyzer bandwidth is set to a value greater than the 20 dB bandwidth of the EUT.

RESULTS

8.5.1. BASIC DATA RATE GFSK MODULATION

Channel	Frequency [MHz]	Output Power [dBm]	Limit [dBm]	Margin [dB]
Low	2402	9.435	21	-11.565
Middle	2441	10.473	21	-10.527
High	2480	8.969	21	-12.031
Worst		10.473	21	-10.527

8.5.2. ENHANCED DATA RATE Pi/4-DPSK MODULATION

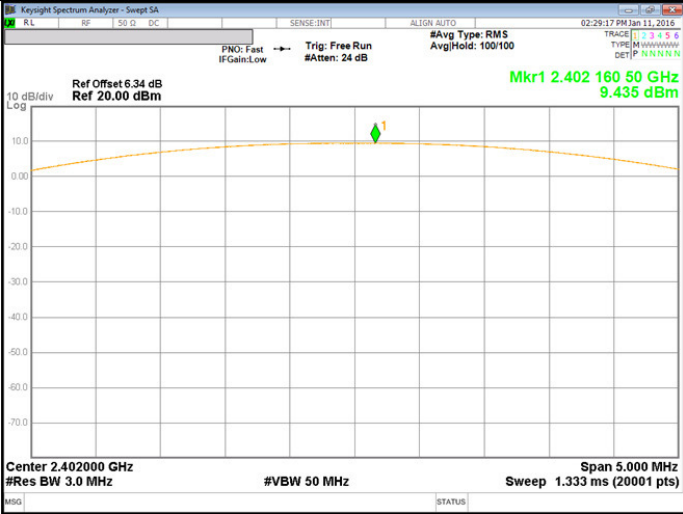
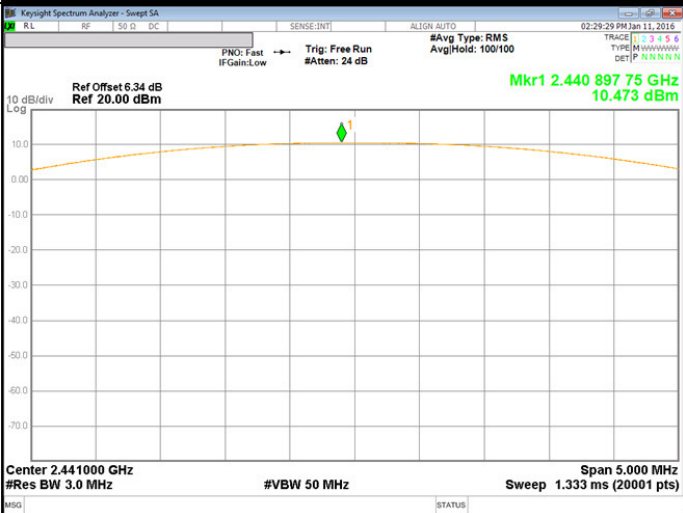
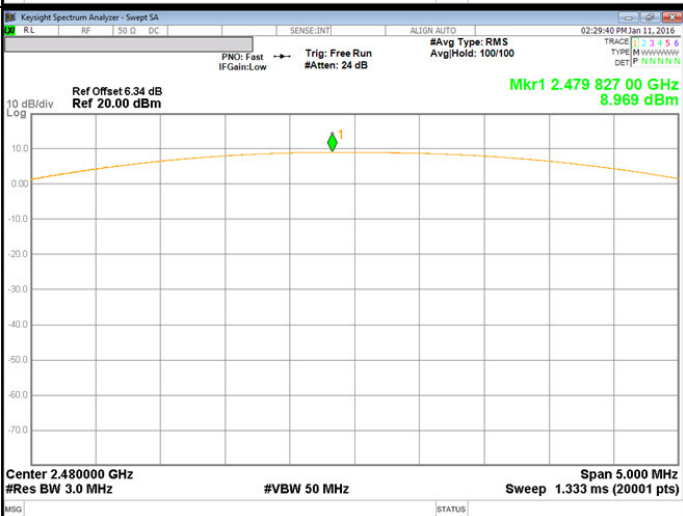
Channel	Frequency [MHz]	Output Power [dBm]	Limit [dBm]	Margin [dB]
Low	2402	10.820	21	-10.180
Middle	2441	11.711	21	-9.289
High	2480	9.984	21	-11.016
Worst		11.711	21	-9.289

8.5.3. ENHANCED DATA RATE 8PSK MODULATION

Channel	Frequency [MHz]	Output Power [dBm]	Limit [dBm]	Margin [dB]
Low	2402	11.123	21	-9.877
Middle	2441	11.965	21	-9.035
High	2480	10.134	21	-10.866
Worst		11.965	21	-9.035

8.5.4. OUTPUT POWER PLOTS

GFSK OUTPUT POWER

GFSK Low CH	 Keyight Spectrum Analyzer - Swept SA Ref Offset 6.34 dB Ref 20.00 dBm Mkr1 2.402 160 50 GHz 9.435 dBm Center 2.402000 GHz #Res BW 3.0 MHz #VBW 50 MHz Sweep 1.333 ms (20001 pts)
GFSK Middle CH	 Keyight Spectrum Analyzer - Swept SA Ref Offset 6.34 dB Ref 20.00 dBm Mkr1 2.440 897 75 GHz 10.473 dBm Center 2.441000 GHz #Res BW 3.0 MHz #VBW 50 MHz Sweep 1.333 ms (20001 pts)
GFSK High CH	 Keyight Spectrum Analyzer - Swept SA Ref Offset 6.34 dB Ref 20.00 dBm Mkr1 2.479 827 00 GHz 8.969 dBm Center 2.480000 GHz #Res BW 3.0 MHz #VBW 50 MHz Sweep 1.333 ms (20001 pts)